



# Leibniz Transactions on Embedded Systems

## Call for Papers

## Special Issue on Embedded System Security

*Embedded systems are now an integral part of our lives. We have smart phones, smart meters, smart appliances, smart cars, smart grids, and smart houses—most relying on embedded systems with outdated security mechanisms, if they have any at all. A renewed emphasis on embedded systems security research is critical to our economy and our daily life.*

The LITES journal has kindly agreed to publish a Special Issue on Embedded System Security. The issue will focus on the following topics:

- Security and dependability of embedded systems,
- Intrusion tolerant embedded systems,
- Confidentiality and privacy in embedded systems,
- System architectures addressing combinations of security, threats, and vulnerabilities in embedded systems.

We are specifically calling for papers that combine several of the existing approaches for embedded systems security, but more generally anything that can advance the state of the art in embedded systems security will be considered.

All articles submitted to this special issue will undergo a rigorous reviewing process of the LITES journal, which will be coordinated by special editors Steve Goddard (University of Iowa) and Alan Burns (University of York). Manuscripts submitted should contain original and in major parts unpublished research work and be of appropriate length for the contents covered, preferably of approximately double the length of a typical conference paper, i.e., up to ca. 30 pages. As usual with LITES, accepted articles are published open access, i.e., accessible online without any costs, and the rights are retained by the author(s).

### Important Dates:

- Full paper submission: ~~March 15, 2020~~ July 15, 2020
- First editorial notice: ~~June 15, 2020~~ October 15, 2020
- Revised submission: ~~July 14, 2020~~ November 14, 2020
- Final decision: ~~August 11, 2020~~ December 11, 2020

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